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Titolo	The youth labor market problem [[electronic resource]] : its nature, causes, and consequences / / edited by Ricard B. Freeman and David A. Wise
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Collana	A National Bureau of Economic Research conference report
Altri autori (Persone)	FreemanRichard B <1943-> (Richard Barry) WiseDavid A
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Nota di contenuto	Front matter -- Contents -- 1. The Youth Labor Market Problem: Its Nature Causes and Consequences -- 2. Teenage Unemployment: What is the Problem? -- 3. The Youth Labor Market Problem in the United States: An Overview -- 4. Why Does the Rate of Youth Labor Force Activity Differ across Surveys? -- 5. Economic Determinants of Geographic and Individual Variation in the Labor Market Position of Young Persons -- 6. Time Series Changes in Youth Joblessness -- 7. The Dynamics of Youth Unemployment -- 8. Labor Turnover and Youth Unemployment -- 9. High School Preparation and Early Labor Force Experience -- 10. Teenage Unemployment: Permanent Scars or Temporary Blemishes? -- 1.1 The Employment and Wage Consequences of Teenage Women's Nonemployment -- 12. Dead-end Jobs and Youth Unemployment -- 13. Family Effects in Youth Employment -- 14. The Minimum Wage and Job Turnover in Markets for Young Workers -- 15. Youth Unemployment in Britain and the United States Compared -- Contributors -- Author Index -- Subject

Index

Sommarioriassunto

This volume brings together a massive body of much-needed research information on a problem of crucial importance to labor economists, policy makers, and society in general: unemployment among the young. The thirteen studies detail the ambiguity and inadequacy of our present standard statistics as applied to youth employment, point out the error in many commonly accepted views, and show that many critically important aspects of this problem are not adequately understood. These studies also supply a significant amount of raw data, furnish a platform for further research and theoretical work in labor economics, and direct attention to promising avenues for future programs.

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Titolo

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Altri autori (Persone)

SchrimpfRonald Donald
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CONTENTS ; Preface ; Single Event Effects in Avionics and on the Ground ; 1.

Introduction ; 2. Similarities between SEE in Avionics and on the Ground ; 3. Differences Between SEE in Avionics and on the Ground ; 4. Atmospheric and Ground Level Environments ; 5. SEE Data in devices

6. Summary Soft Errors in Commercial Integrated Circuits ; 1. Introduction ; 2. Scaling trends for memory devices ; 3. Seating trend for peripheral logic devices ; 4. Conclusion ; Single-Event Effects in III-V Semiconductor Electronics ; 1. Introduction 2. Single-Event Effects in III-V Electronic Devices 3. Summary and Conclusions ; Investigation of Single-Event Transients in Fast Integrated Circuits with a Pulsed Laser ; 1. Basic Mechanisms of a SET ; 2. SET Laser Testing ; 3. Experimental set-up for SET laser testing ; 4. Results 5. Conclusions System Level Single Event Upset Mitigation Strategies ; 1. Introduction ; 2. Systems Engineering for Energetic Particle Environment Compatibility ; 3. Fault Tolerant Systems Strategies ; Radiation-Tolerant Design for High Performance Mixed-Signal Circuits 1. Introduction 2. Radiation Mechanisms in Mixed-Signal Integrated Circuits ; 3. Process Component and Layout Choices for Hardened-by-Design Circuits ; 4. Total Dose Hardening ; 5. Single-Event Effect Hardening ; 6. Dose-Rate Effect Hardening ; 7. Conclusion A Total-Dose Hardening-By-Design Approach for High-Speed Mixed-Signal CMOS Integrated Circuits

Sommario/riassunto

This book provides a detailed treatment of radiation effects in electronic devices, including effects at the material, device, and circuit levels. The emphasis is on transient effects caused by single ionizing particles (single-event effects and soft errors) and effects produced by the cumulative energy deposited by the radiation (total ionizing dose effects). Bipolar (Si and SiGe), metal-oxide-semiconductor (MOS), and compound semiconductor technologies are discussed. In addition to considering the specific issues associated with high-performance devices and technologies, the book includes t